



TIB modules test results from Bari

(D. Giordano - S. My)

- Optical Inspection System
- Hybrid Test (ARC-System) before Assem.
- Module Assembling
- Hybrid Test (ARC-System) after Assem.
- Bonding
- Module Test (CMS-like System)



Test results for:

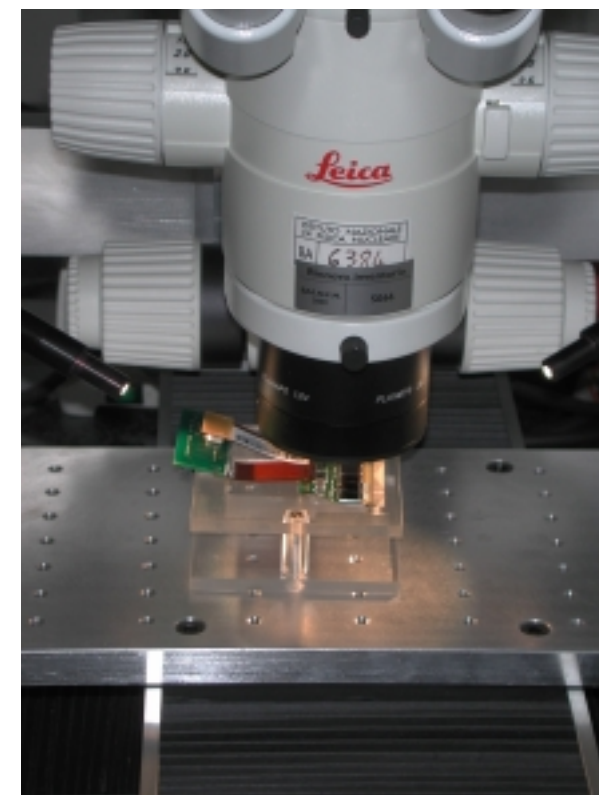
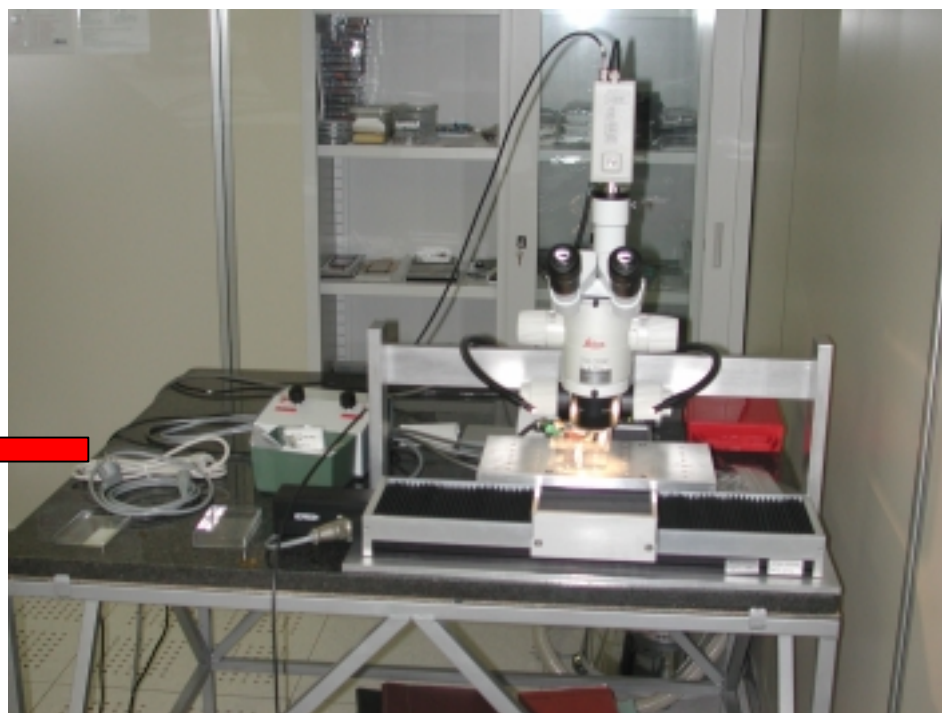


| <u>TIB009</u> | <u>TIB010</u> |
|--|---|
| <ul style="list-style-type: none">•2 CSEM Sensors (daisy chained)•Ceramic Hybrid (4 APVs) | <ul style="list-style-type: none">•2 CSEM Sensors (daisy chained)•Fr4_v1 Hybrid (4 APVs) |

Fr4_v2 Hybrid
6 APVs (Only 4 connected to PA)
(preliminary results)



Optical Inspection System





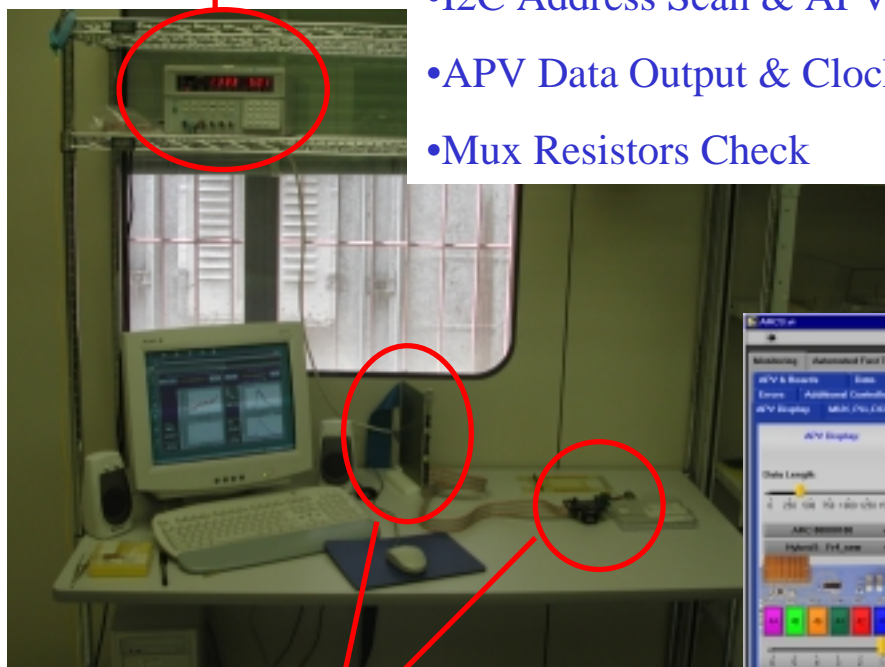
ARC System Setup



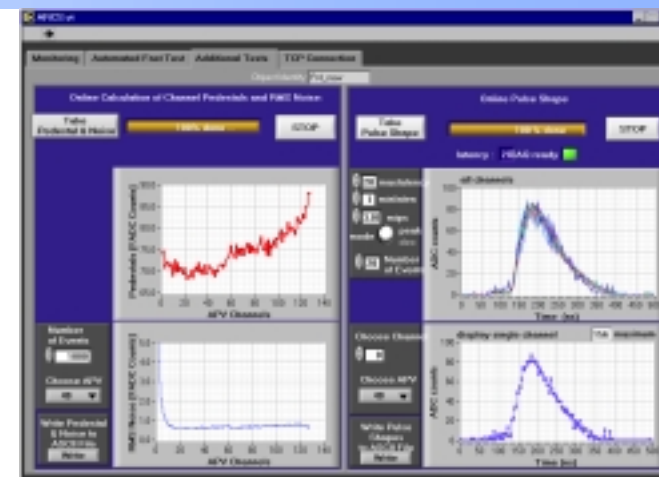
Automated Fast Test

- Self Test ARC System
- Low Voltage Control
- I2C Address Scan & APV R/W Cycles
- APV Data Output & Clock Distribution
- Mux Resistors Check

LV-Source
(+5 V , -5V)



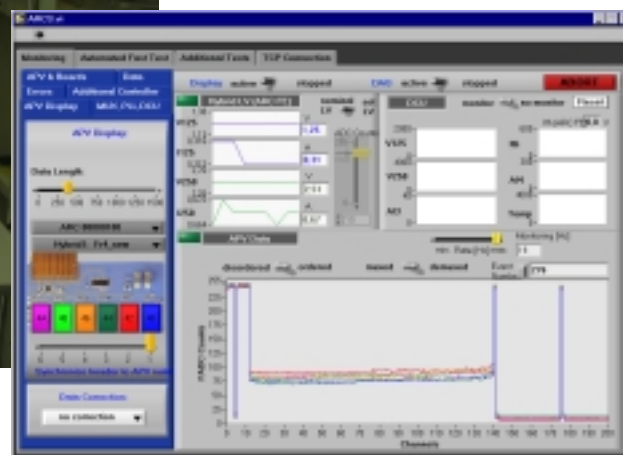
ARC System



Noise, Pedestal & Calibration

APV Settings

| | |
|--------|----|
| IPRE | 98 |
| IPCASC | 52 |
| IPSF | 34 |
| ISHA | 34 |
| ISSF | 34 |
| IPSP | 55 |
| IMUXIN | 34 |
| ICAL | 29 |
| VFP | 30 |
| VFS | 60 |
| VPSP | 40 |





Ceramic hybrid Noise

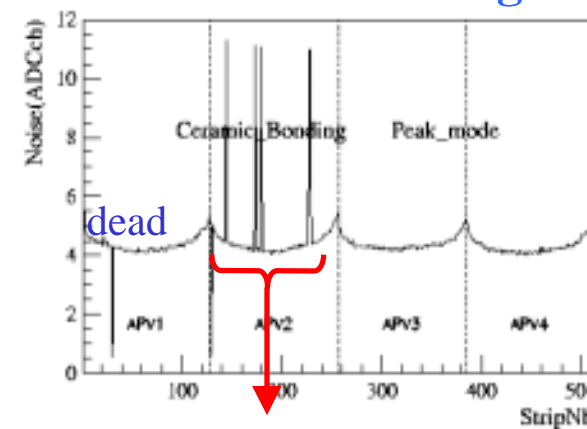
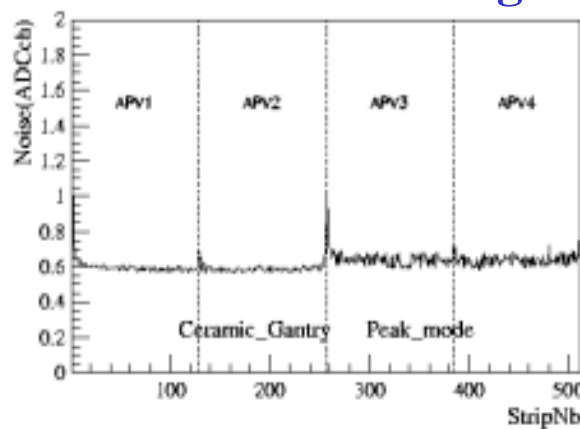
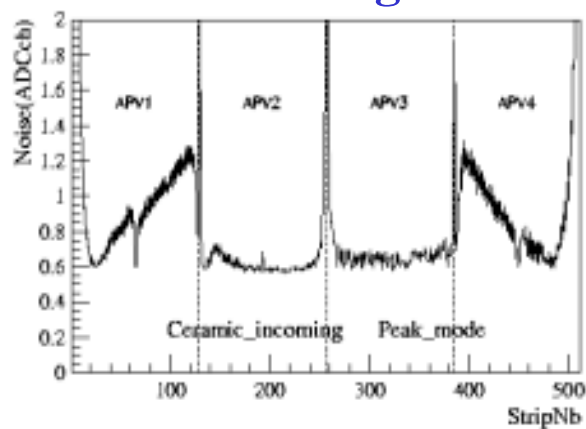


Incoming

After Assembling

After Bonding

Peak

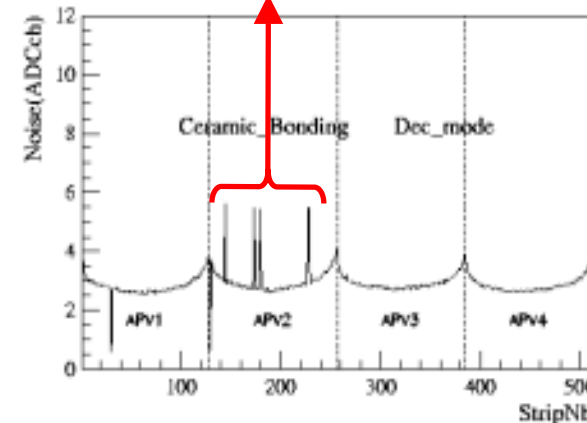
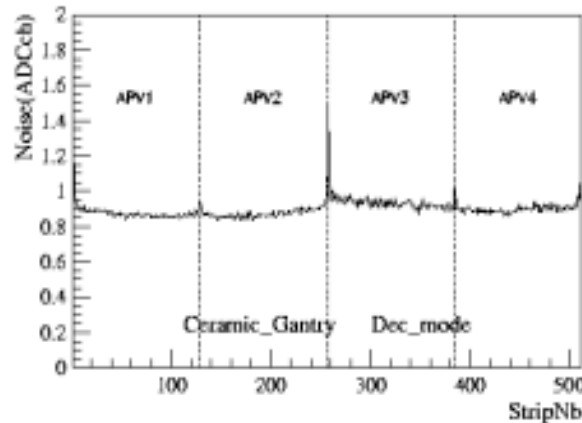
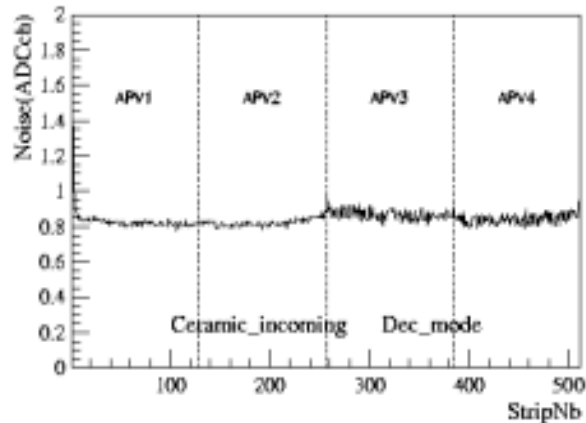


PA structure ?



Missing bonding:
143,172,178,226,227

Dec



no HV

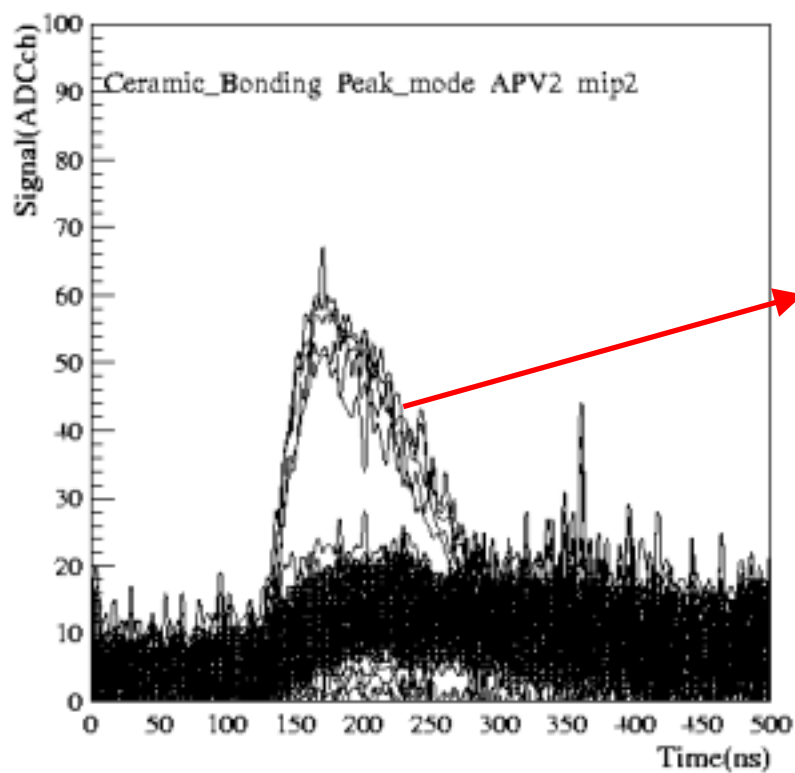


Ceramic Calibration Psh

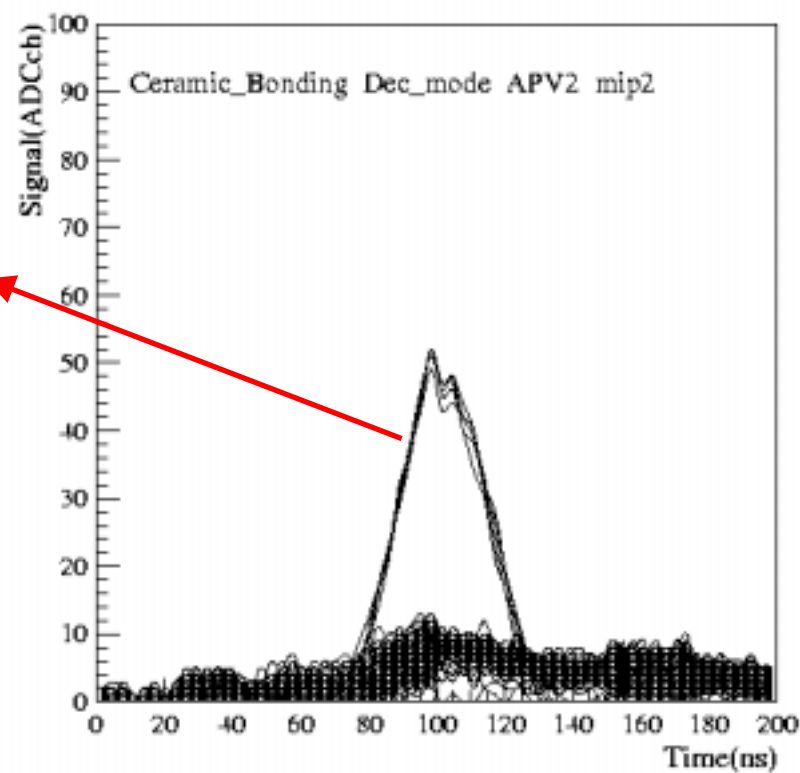


APV2 After Bonding (no HV)

Peak



Dec



missing
bonding:
143,172,
178,226,
227



Fr4_v1 hybrid Noise

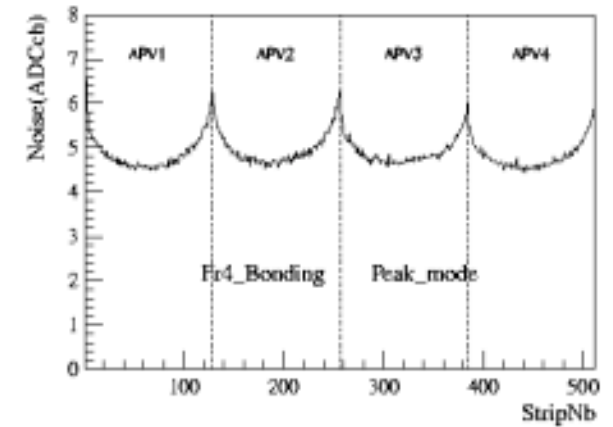
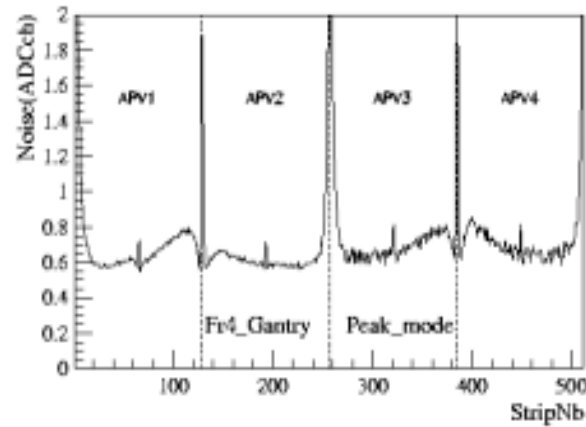
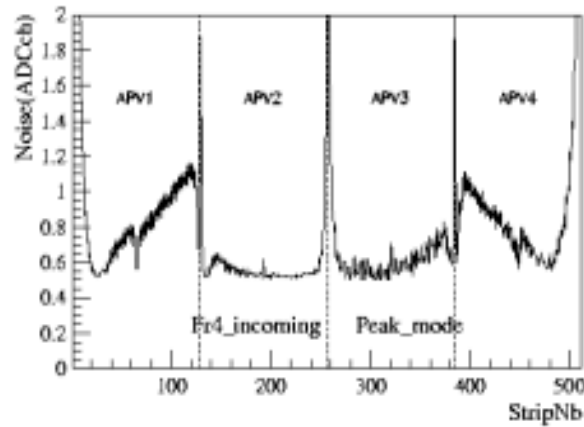


Incoming

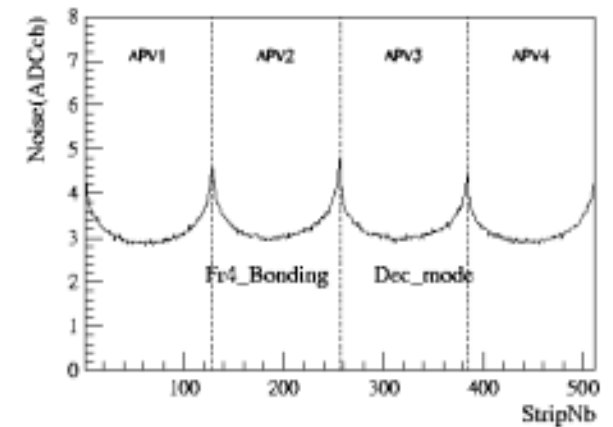
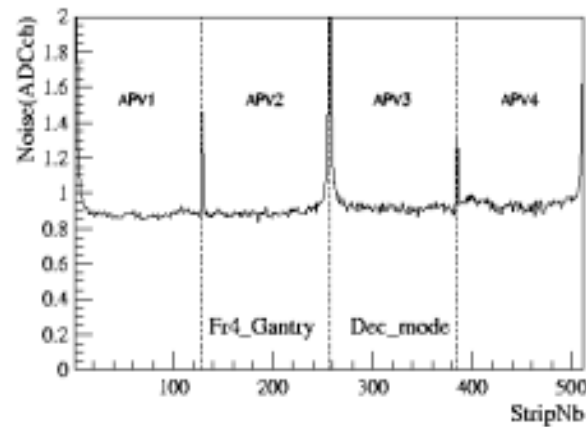
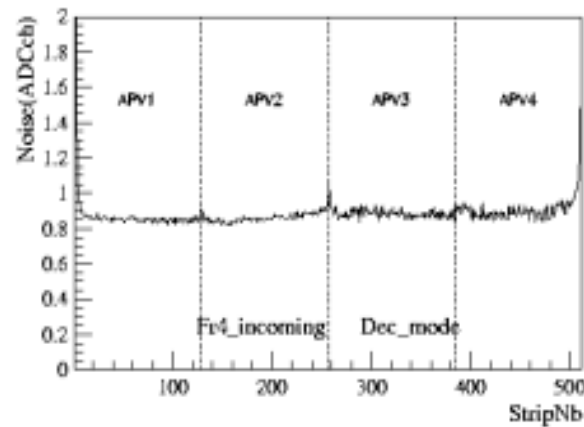
After Assembling

After Bonding

Peak



Dec



No HV

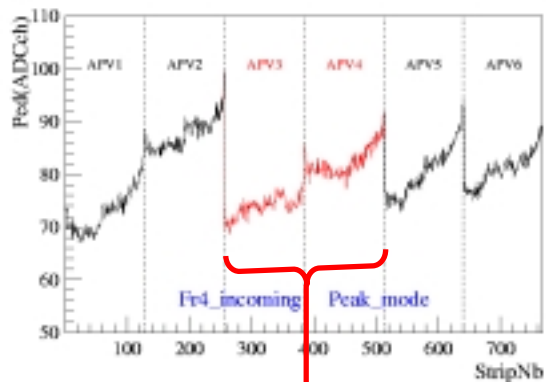


Fr4_v2 hybrid (Version 2)

(Peak mode)

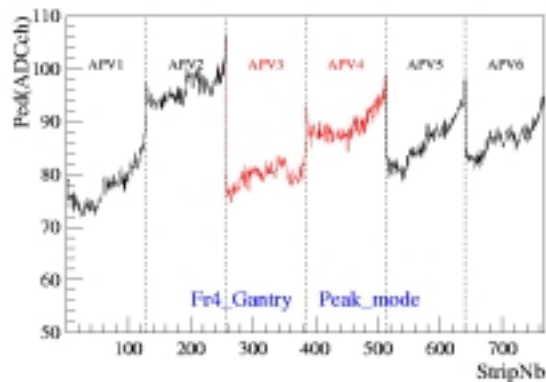


Incoming



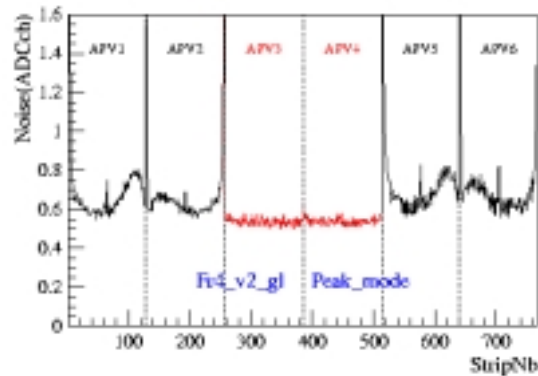
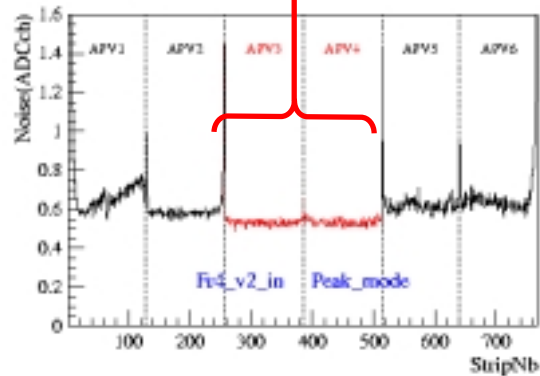
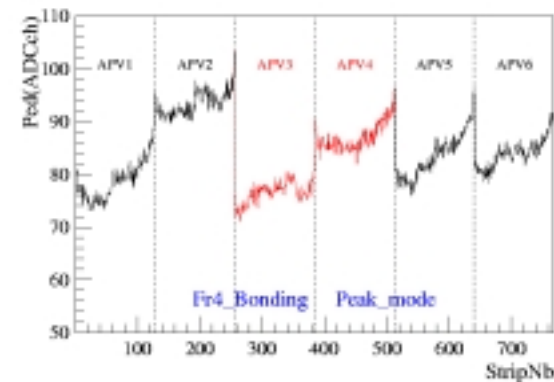
APVs not-connected

After Assembling

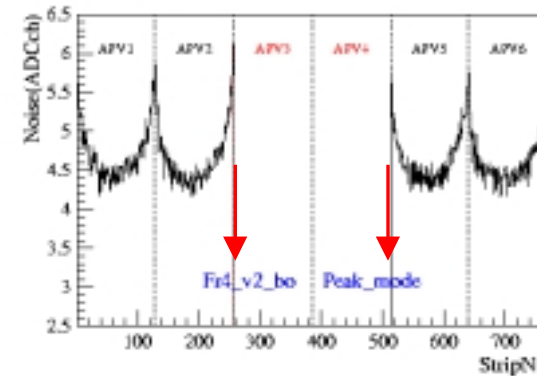


Pedestal

After Bonding



Noise



no HV



CMS-like System Setup



Lyon DAQ with TSC

analysis tool: Torino macro

TIB009

Depletion Voltage: 220 V

Bias: 300 V

$I \sim 8 \mu\text{A}$

TIB010

Depletion Voltage: 200 V

Bias: 300 V

$I \sim 13 \mu\text{A}$



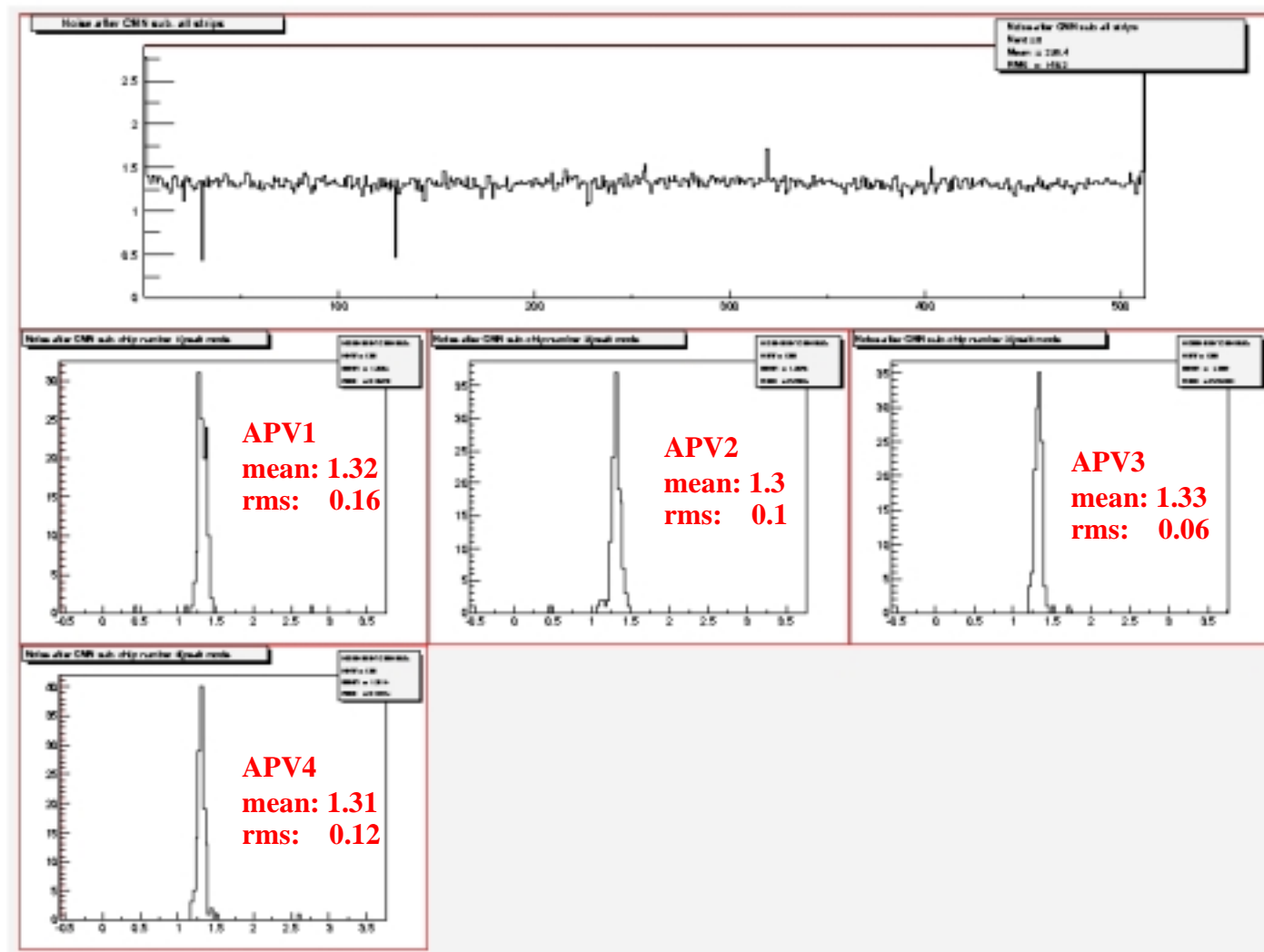


TIB009 Noise

(after CMN subtraction)



Peak



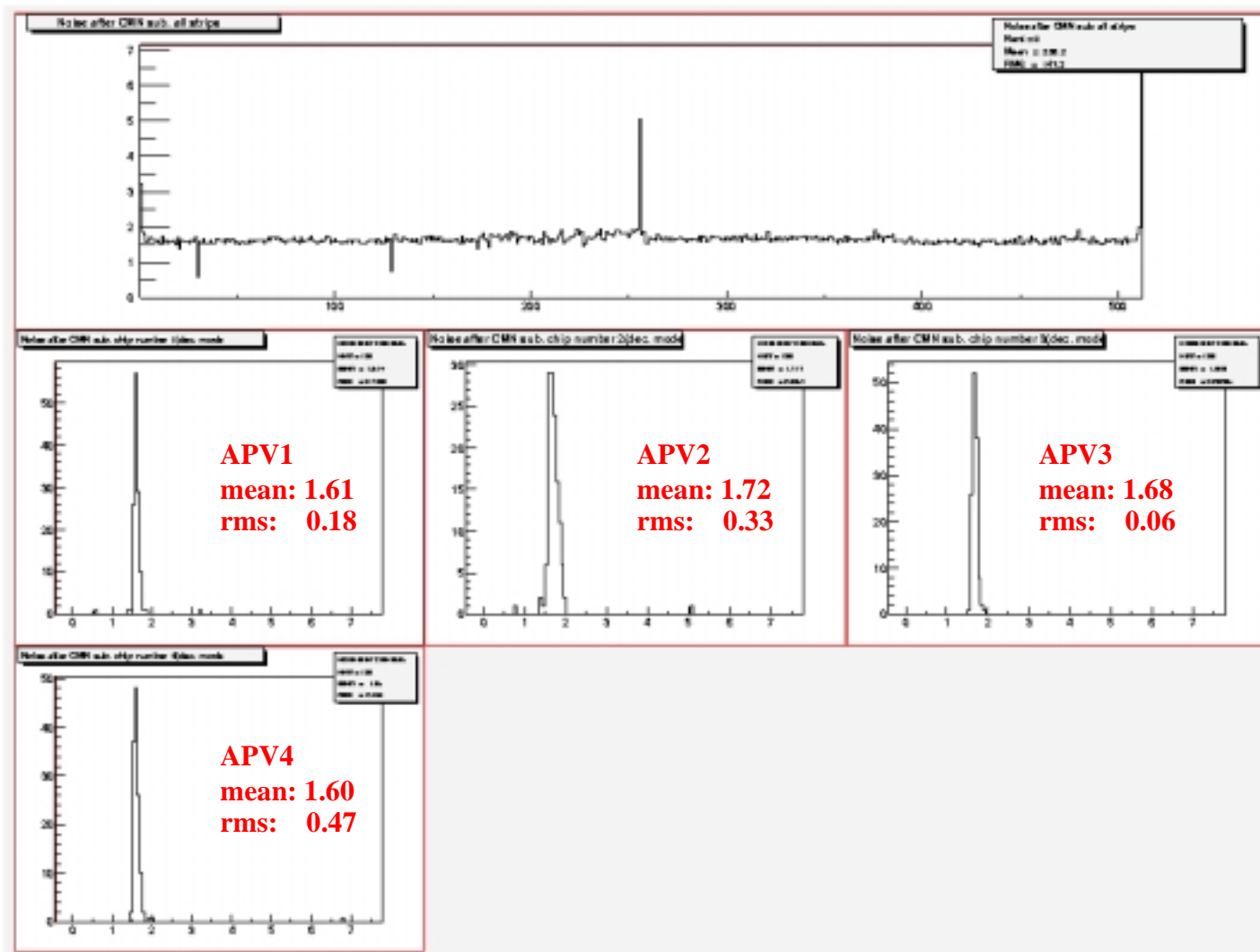


TIB009 Noise

(after CMN subtraction)



Dec





TIB009 Bad Strips



Number of bad strips 16:

| | | | | | |
|--------|-----------|------|--------------------------|-----|-------------------------|
| chip 1 | strip 1 | peak | Raw Noise + Noise; | dec | Raw Noise + Noise |
| chip 1 | strip 21 | peak | OK; | dec | Calibration |
| chip 1 | strip 30 | peak | Raw Noise + Noise + Cal; | dec | as peak |
| chip 1 | strip 128 | peak | OK; | dec | Raw Noise |
| chip 2 | strip 129 | peak | Raw Noise + Noise + Cal; | dec | Raw Noise + Noise + Cal |
| chip 2 | strip 144 | peak | OK; | dec | Calibration |
| chip 2 | strip 173 | peak | OK; | dec | Calibration |
| chip 2 | strip 179 | peak | OK; | dec | Calibration |
| chip 2 | strip 227 | peak | Raw Noise; | dec | Calibration |
| chip 2 | strip 228 | peak | OK; | dec | Calibration |
| chip 2 | strip 256 | peak | Raw Noise; | dec | Raw Noise + Noise |
| chip 3 | strip 319 | peak | Raw Noise + Noise; | dec | OK |
| chip 3 | strip 384 | peak | OK; | dec | Raw Noise |
| chip 4 | strip 480 | peak | OK; | dec | Raw Noise |
| chip 4 | strip 511 | peak | OK; | dec | Raw Noise |
| chip 4 | strip 512 | peak | Raw Noise + Noise; | dec | Raw Noise + Noise |

⇒ unbonded strips on APV2

Cut methods:
cuts in chip average value
percentage

Pedestal: low 0.10 high 0.10
 Noise: low 0.20 high 0.20
 RNoise : low 0.20 high 0.20
 Calibration: low 0.20 high 0.10

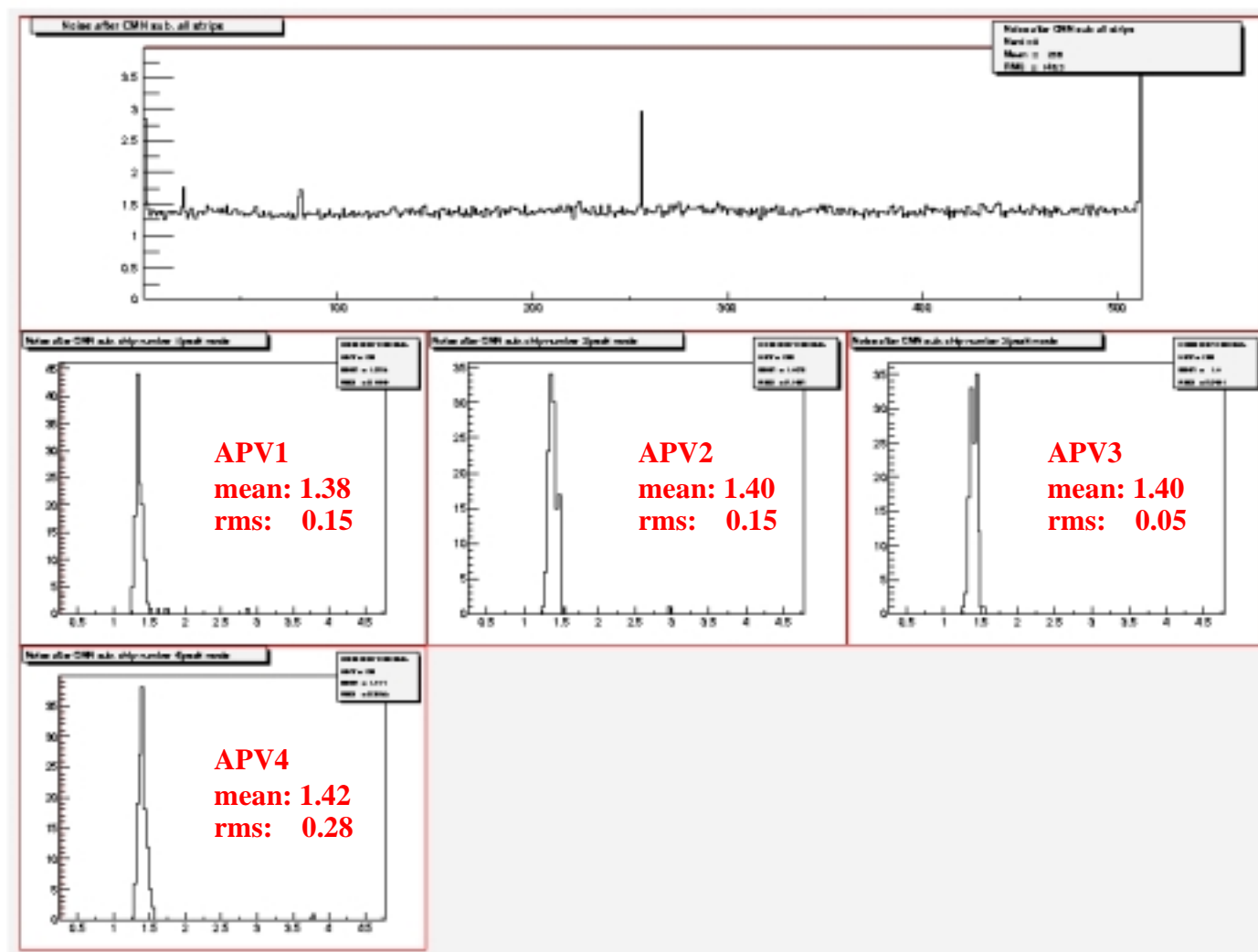


TIB010 Noise

(after CMN subtraction)



Peak



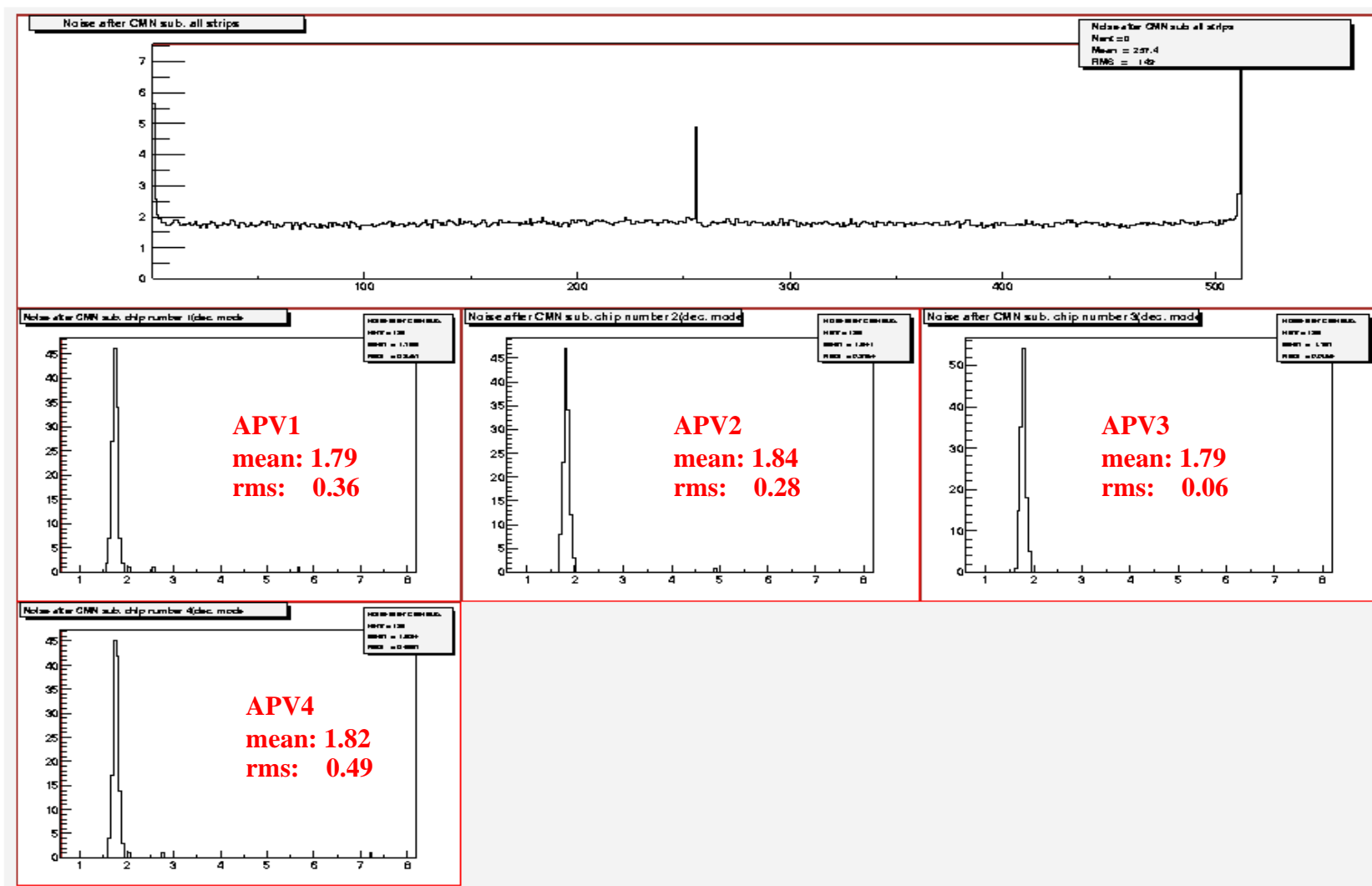


TIB010 Noise

(after CMN subtraction)



Dec





TIB010 Bad Strips



Cut methods:
cuts in chip average value percentage

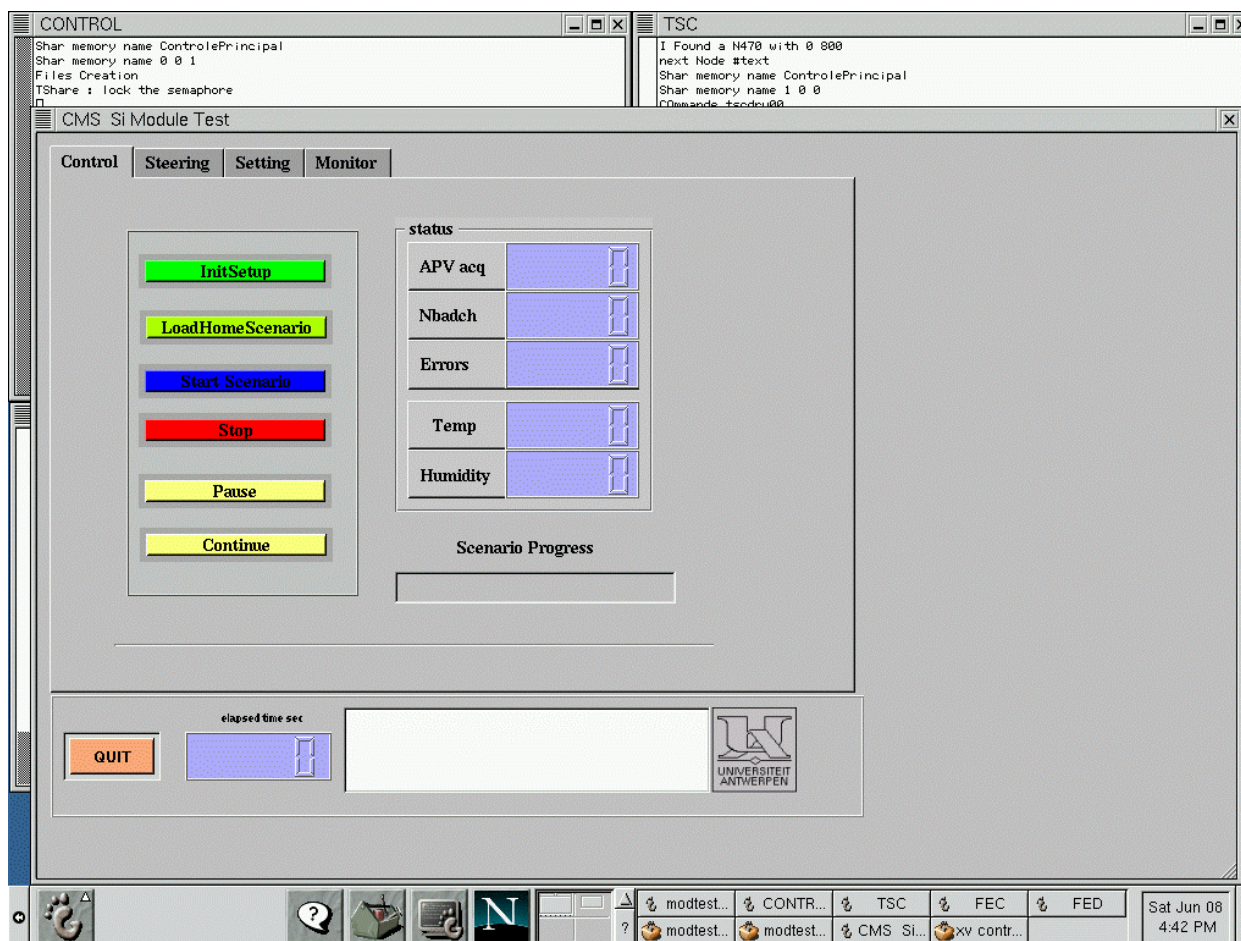
Pedestal: low 0.10 high 0.10
Noise: low 0.20 high 0.20
RNoise : low 0.20 high 0.20
Calibration: low 0.20 high 0.10

Number of bad strips 8:

| | | | | |
|------------------|------|--------------------|-----|-------------------|
| chip 1 strip 1 | peak | Raw Noise + Noise; | dec | Raw Noise + Noise |
| chip 1 strip 2 | peak | OK; | dec | Raw Noise + Noise |
| chip 1 strip 21 | peak | Raw Noise + Noise; | dec | OK |
| chip 1 strip 81 | peak | Noise; | dec | OK |
| chip 2 strip 256 | peak | Raw Noise + Noise; | dec | Raw Noise + Noise |
| chip 2 strip 257 | peak | OK; | dec | Raw Noise |
| chip 4 strip 511 | peak | OK; | dec | Raw Noise + Noise |
| chip 4 strip 512 | peak | Raw Noise + Noise; | dec | Raw Noise + Noise |



Antwerpen's Sw



- installed last week
- module test foreseen next week

Next Step:
implement temperature
and umidity sensors
(Wien TRHX)